

Manufacturer: JEOL Ltd., Japan.

Intended Use: The instrument will be used for ultrastructural diagnosis of patient material, and for ultrastructural research using both human and animal tissues necessary in the treatment of veterans. In addition, the instrument will be used for the training on a one-to-one basis of medical and graduate students. *Application accepted by Commissioner of Customs:* July 23, 1996.

Docket Number: 96-082. *Applicant:* Florida State University, MBB 151, Tallahassee, FL 32306-3015.

Instrument: Electron Microscope, Model CM120. *Manufacturer:* Philips, The Netherlands. *Intended Use:* The instrument will be used in research studies to examine the ultrastructure of cells and how it relates to biological function and disease processes. Experiments will involve isolation of protein and assemblies, growth of 2-D crystalline arrays of protein followed by examination in the microscope. The instruments will also be used for trial studies in structure-based drug design to demonstrate the feasibility of using electron crystallography in this area. *Application accepted by Commissioner of Customs:* July 24, 1996.

Frank W. Creel,

Director, Statutory Import Programs Staff.

[FR Doc. 96-20935 Filed 8-15-96; 8:45 am]

BILLING CODE 3510-DS-P

University of Illinois at Urbana-Champaign, et al.; Notice of Consolidated Decision on Applications for Duty-Free Entry of Scientific Instruments

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5:00 p.m. in Room 4211, U.S. Department of Commerce, 14th and Constitution Avenue, N.W., Washington, D.C.

Comments: None received. *Decision:* Approved. No instrument of equivalent scientific value to the foreign instruments described below, for such purposes as each is intended to be used, is being manufactured in the United States.

Docket Number: 96-019. *Applicant:* University of Illinois at Urbana-Champaign, Urbana, IL 61801.

Instrument: Stopped-Flow Reaction Analyser, Model SX.17MV. *Manufacturer:* Applied Photophysics Ltd., United Kingdom. *Intended Use:* See notice at 61 FR 25622, May 22,

1996. *Reasons:* The foreign instrument provides simultaneous measurements across the entire white-light spectrum with high beam stability using a diode array detector.

Docket Number: 96-038. *Applicant:* Purdue University, West Lafayette, IN 47907. *Instrument:* Stopped-Flow Fluorimeter, Model SX.17MV. *Manufacturer:* Applied Photophysics Ltd., United Kingdom. *Intended Use:* See notice at 61 FR 28177, June 4, 1996. *Reasons:* The foreign instrument provides automated multiple mixing using a 4-syringe drive unit under computer control.

Docket Number: 96-039. *Applicant:* Columbia University, Lamont-Doherty Observatory, Palisades, NY 10964-8000. *Instrument:* Mass Spectrometer, Model VG 5400. *Manufacturer:* Fisons Instruments, United Kingdom. *Intended Use:* See notice at 61 FR 28177, June 4, 1996. *Reasons:* The foreign instrument provides (1) a low background count rate at mass 36 (less than 5×10^{-14} cc STP) and (2) a desorption rate less than 10^{-17} cc STP/min of 40Ar.

Docket Number: 96-040. *Applicant:* Washington University, St. Louis, MO 63130-4899. *Instrument:* ICP Mass Spectrometer, Model ELEMENT. *Manufacturer:* Finnigan MAT, Germany. *Intended Use:* See notice at 61 FR 28177, June 4, 1996. *Reasons:* The foreign instrument provides a magnetic sector analyzer with resolution to 7500 for precise and accurate low level (sub ppb) measurements of the transition elements.

Docket Number: 96-042. *Applicant:* University of Kansas, Lawrence, KS 66045. *Instrument:* Mass Spectrometer, Model PlasmaQuad XS. *Manufacturer:* Fisons Instruments, Inc., United Kingdom. *Intended Use:* See notice at 61 FR 28177, June 4, 1996. *Reasons:* The foreign instrument provides: (1) sub ppt detection limits for Li, Cs, Pb, U and In, (2) sensitivity >20 Mcps/ppm for heavy elements and (3) UV laser ablation capability.

The capabilities of each of the foreign instruments described above are pertinent to each applicant's intended purposes. We know of no instrument or apparatus being manufactured in the United States which is of equivalent scientific value to any of the foreign instruments.

Frank W. Creel,

Director, Statutory Import Programs Staff.

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BILLING CODE 3510-DS-P

University of Wisconsin, et al.; Notice of Consolidated Decision on Applications for Duty-Free Entry of Scientific Instruments

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Room 4211, U.S. Department of Commerce, 14th and Constitution Avenue, N.W., Washington, D.C.

Comments: None received. *Decision:* Approved. No instrument of equivalent scientific value to the foreign instruments described below, for such purposes as each is intended to be used, is being manufactured in the United States.

Docket Number: 95-085R. *Applicant:* University of Wisconsin-Eau Claire, Eau Claire, WI 54702. *Instrument:* Absorbance and Fluorescence Stopped-Flow Spectrophotometer, Model SX.17MV. *Manufacturer:* Applied Photophysics Ltd., United Kingdom. *Intended Use:* See notice at 60 FR 50555, September 29, 1995. *Reasons:* The foreign instrument provides a fast enough dead time for observation of rapid reactions with rate constants approaching 1500 reciprocal seconds. *Advice received from:* The National Institutes of Health, June 10, 1996.

Docket Number: 96-029. *Applicant:* University of Iowa, Iowa City, IA 52242. *Instrument:* EPR Spectrometer, Model EMX 6/1. *Manufacturer:* Bruker Instruments, Germany. *Intended Use:* See notice at 61 FR 28176, June 4, 1996. *Reasons:* The foreign instrument provides a multifrequency single-channel cavity with a continuous range of modulation frequencies from 6 kHz to 100 kHz with a resolution of 0.01 kHz. *Advice received from:* The National Institutes of Health, March 29, 1996.

Docket Number: 96-033. *Applicant:* University of Southern California, Los Angeles, CA 90089-2520. *Instrument:* Xenon Flashlamp System, Model XF-10. *Manufacturer:* Hi-Tech Scientific, United Kingdom. *Intended Use:* See notice at 61 FR 28176, June 4, 1996. *Reasons:* The foreign instrument provides: (1) a high voltage power supply integrated and coupled to a xenon flashlamp system and (2) time resolution in the millisecond range with moderate repetition rates. *Advice received from:* The National Institutes of Health, March 29, 1996.

Docket Number: 96-045. *Applicant:* Monell Chemical Senses Center, Philadelphia, PA 19104-3308. *Instrument:* Xenon Flashlamp System,